

Docket No.: 56799/A400
Amdt date December 28, 2005

Amendments to the Specification:

Please delete the current title and replace with the following:

-- PATTERN COMPARISON INSPECTION METHOD AND PATTERN COMPARISON
INSPECTION APPARATUS --.

After the title please add the following:

-- CROSS-REFERENCE TO RELATED APPLICATION

This application is a National Phase Patent Application of International Application Number PCT/JP2004/009503, filed on June 29, 2004, which claims priority of Japanese Patent Application Number 2003-187479, filed on June 30, 2003. --.